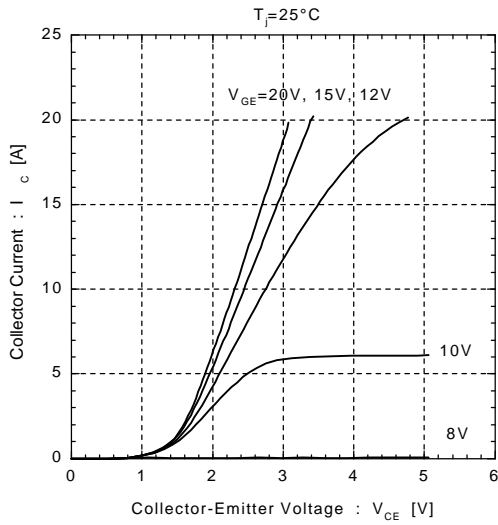
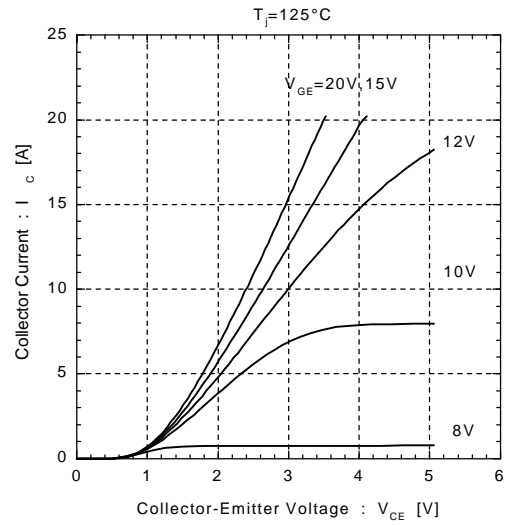


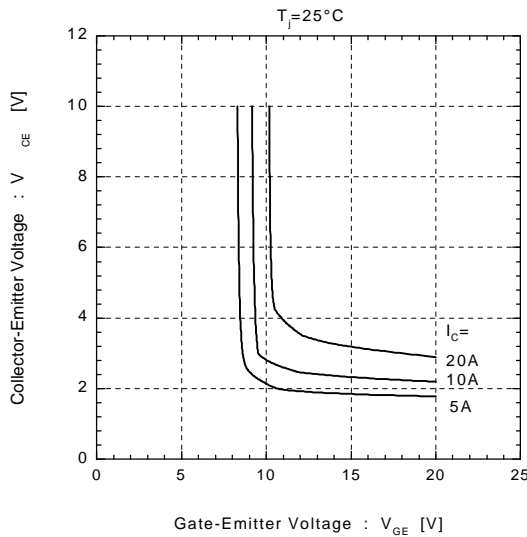
Collector Current vs. Collector-Emittor Voltage



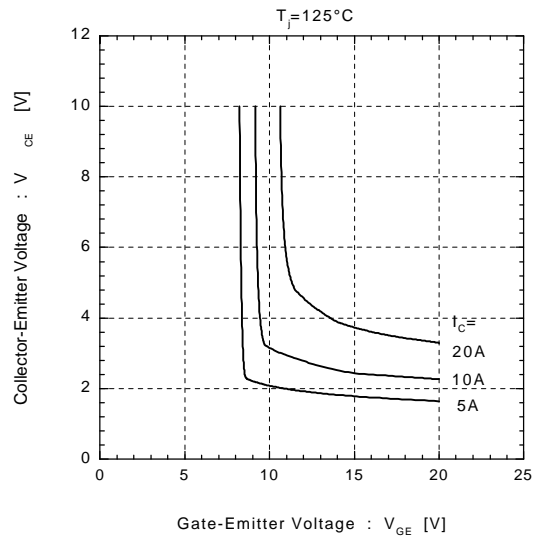
Collector Current vs. Collector-Emittor Voltage



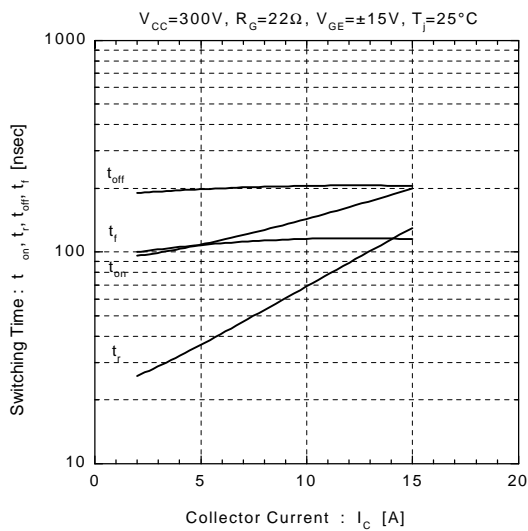
Collector-Emittor Voltage vs. Gate-Emittor Voltage



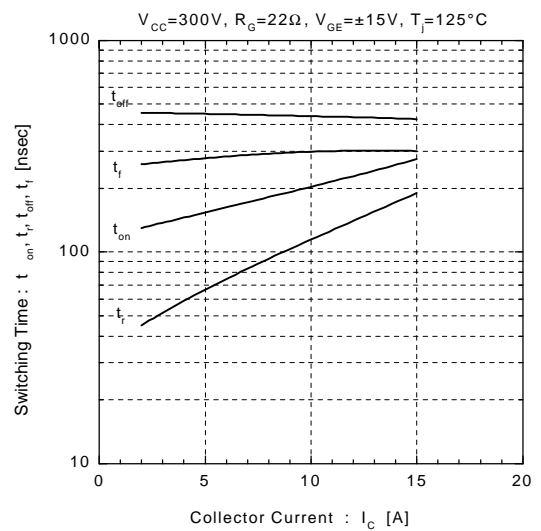
Collector-Emittor Voltage vs. Gate-Emittor Voltage

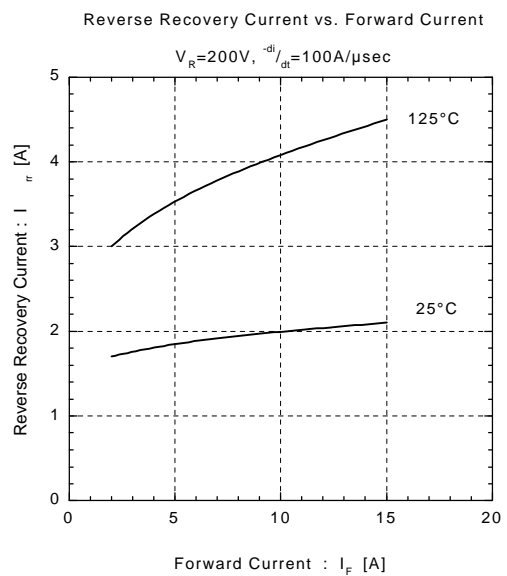
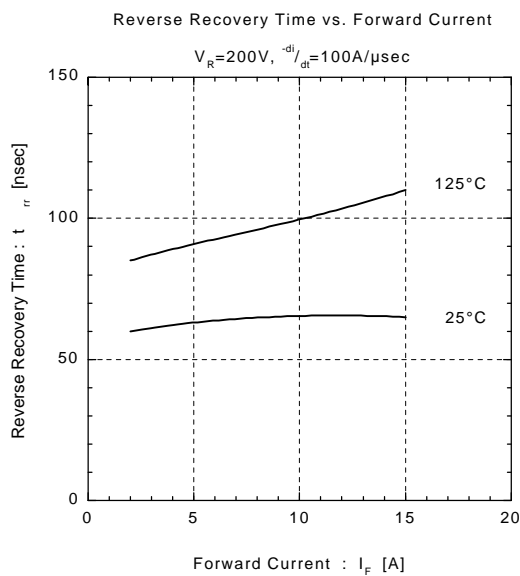
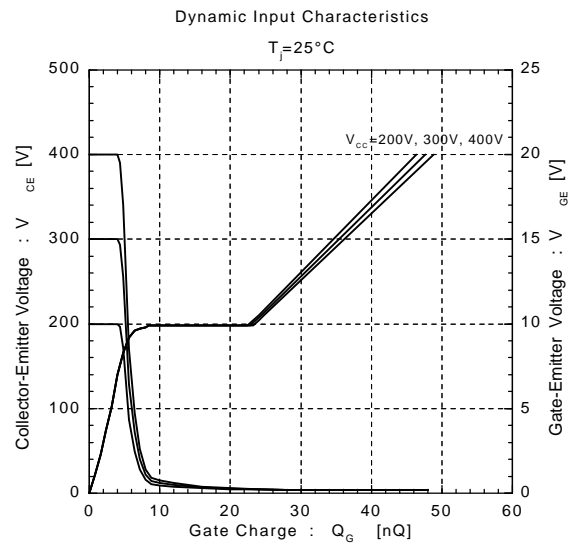
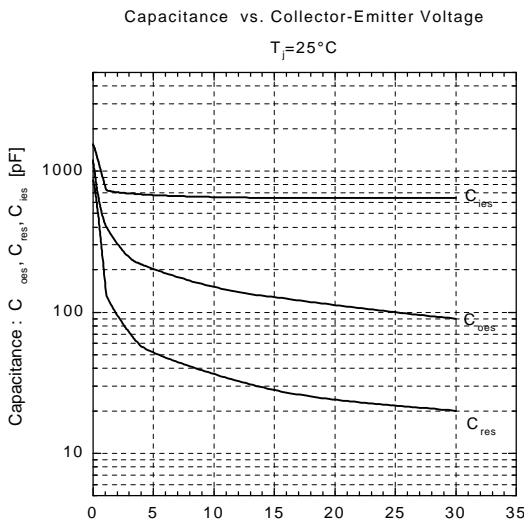
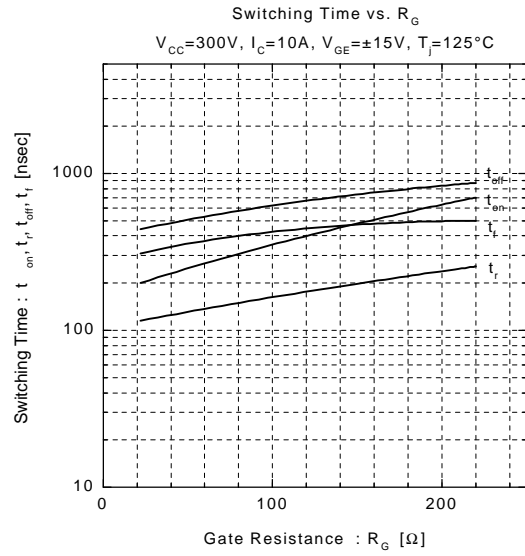
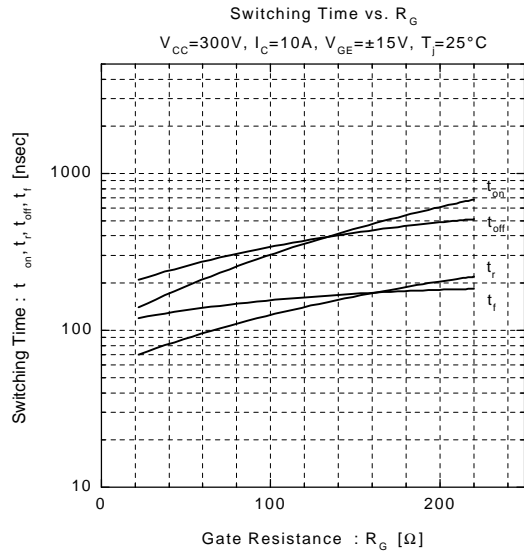


Switching Time vs. Collector Current

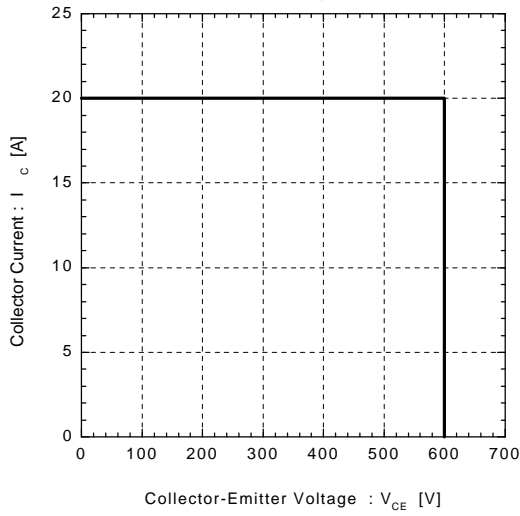


Switching Time vs. Collector Current

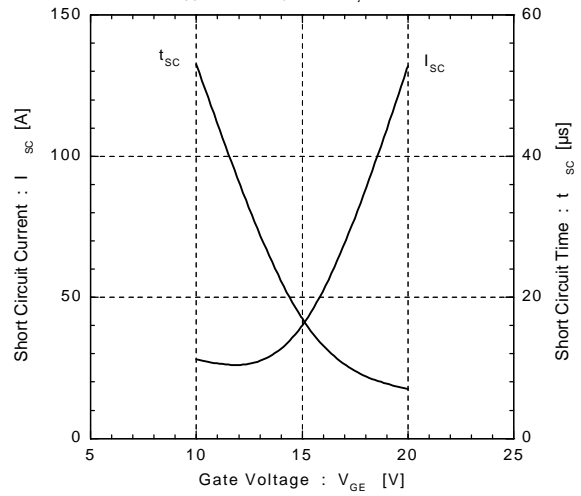




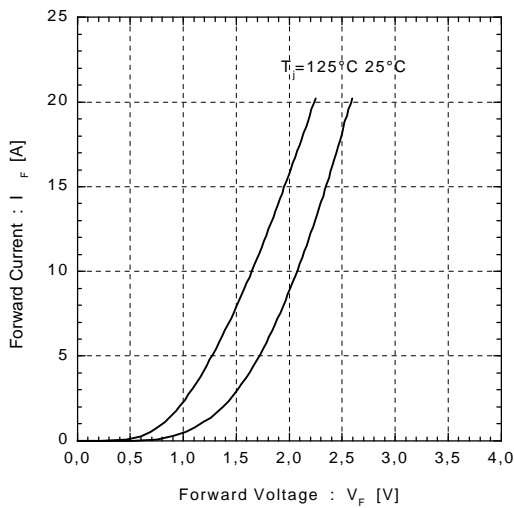
Reverse Biased Safe Operating Area
 $+V_{GE}=15V, -V_{GE}\leq 15V, T_J\leq 125^\circ C, R_G\geq 22\Omega$



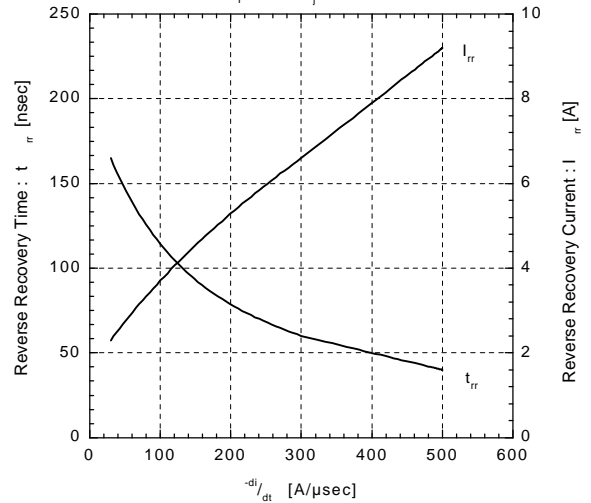
Typical Short Circuit Capability
 $V_{CC}=400V, R_G=22\Omega, T_J=125^\circ C$



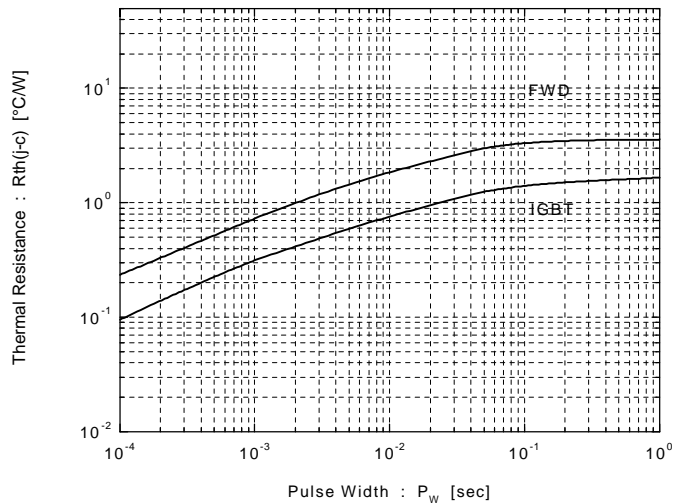
Forward Voltage vs. Forward Current



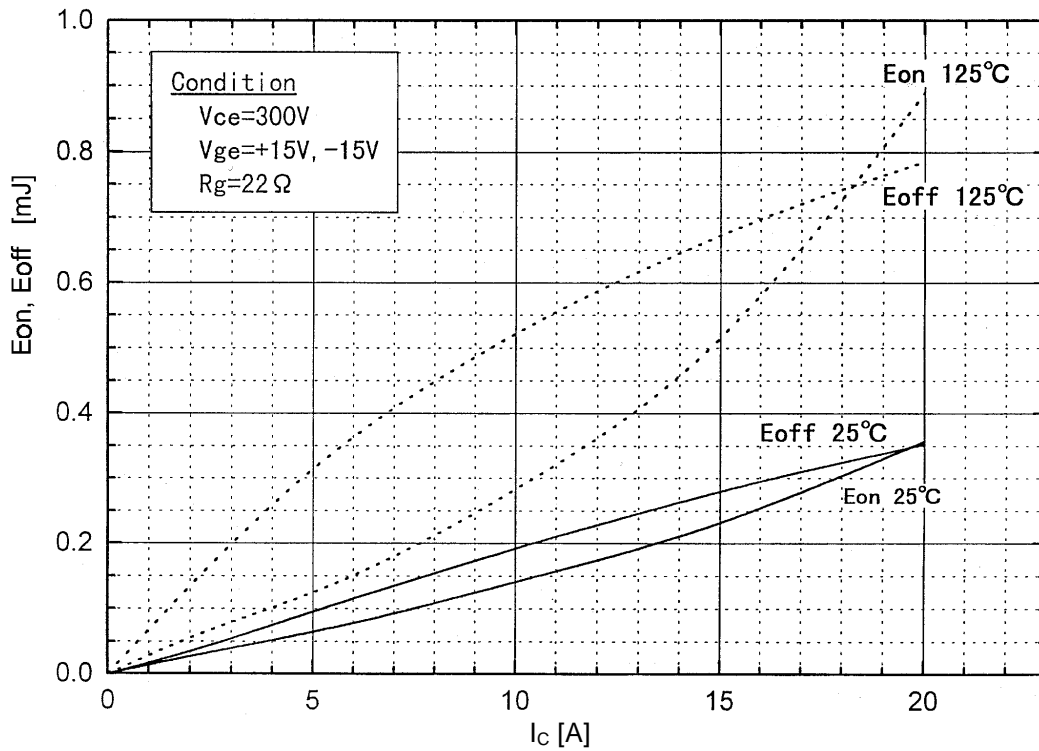
Reverse Recovery Characteristics vs. $-di/dt$
 $I_F=10A, T_J=125^\circ C$



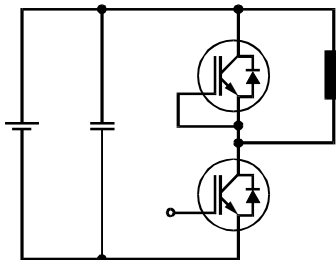
Transient Thermal Resistance



Switching losses (E_{on} , E_{off} vs. I_c)



Test Circuit



Switching waveforms

